Device Modeling Report

COMPONENTS: OPERATIONAL AMPLIFIER (CMOS)

PART NUMBER: NJU7017

MANUFACTURER: NEW JAPAN RADIO



Bee Technologies Inc.

Spice Model



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*CMOS OPAMP

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.SUBCKT nju7017 IN+ V- IN- OUT V+

m1 3 IN- 6 V- nix I=6u w=25u

m2 4 7 6 V- nix l=6u w=25u

m3 8 IN- 5 5 pix l=6u w=23.15u

m4 9 7 5 5 pix l=6u w=25u

eos 7 IN+ poly(1) 25 98 1e-3 0.451

iin1 IN+ 98 1.25p

iin2 IN- 98 1.25p

ios IN- IN+ 0.5p

i1 V+ 5 50u

i2 6 V- 50u

r1 V+ 3 4.833k

r2 V+ 4 4.833k

r3 8 V- 4.833k

r4 9 V- 4.833k

d3 5 V+ dx

d4 V- 6 dx

eref 98 0 poly(2) V+ 0 V- 0 0 0.75 0.75

g1 98 21 poly(2) 4 3 9 8 0 145u 145u

rg 21 98 18.078e6

cc 21 OUT 20p

d1 21 22 dx

d2 23 21 dx

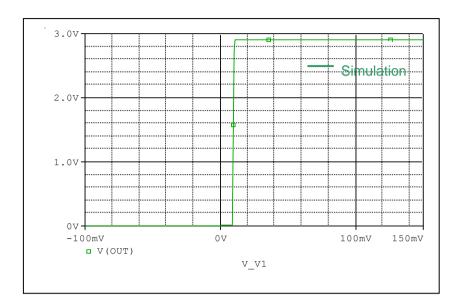
```
v1 V+ 22 1.237
v2 23 V- 1.237
ecm 24 98 poly(2) IN+ 98 IN- 98 0 0.5 0.5
r5 24 25 1e6
r6 25 98 1.3k
c1 24 25 0.75p
isy V+ V- 450.4u
gsy V+ V- poly(1) V+ V- -3.334e-4 6.667e-5
ep V+ 39 poly(1) 98 21 0.8925 1
en 38 V-poly(1) 21 98 0.8925 1
m15 OUT 39 V+ V+ pox I=1.5u w=9u
m16 OUT 38 V- V- nox I=1.5u w=33u
c15 OUT 39 1p
c16 OUT 38 1p
.model dx d(rs=1 cjo=0.1p)
.model nix nmos( vto=.75 kp=205.5u rd=1 rs=1
+ rg=1 rb=1 cgso=4e-9 cgdo=4e-9 cgbo=16.667e-9
+ cbs=7e-12 cbd=7e-12)
.model nox nmos( vto=0.48 kp=195u rd=1.5 rs=1.5
+ rg=1 rb=1 cgso=66.667e-12 cgdo=66.667e-12
+ cgbo=125e-9 cbs=2.34e-13 cbd=2.34e-13)
.model pix pmos( vto=-0.75 kp=205.5u rd=1 rs=1
+ rg=1 rb=1 cgso=4e-9 cgdo=4e-9 cgbo=16.667e-9
+ cbs=2.34e-13 cbd=2.34e-13)
.model pox pmos( vto=-0.75 kp=195u rd=.5 rs=.5
+ rg=1 rb=1 cgso=66.667e-12 cgdo=66.667e-12
+ cgbo=125e-9 cbs=15.38e-11 cbd=15.38e-11)
.SUBCKT DbreakZ A K
D1 A K DF
DZ A2 A DR
VZ K A2 1
.MODEL DF D
.MODEL DR D
.ENDS DbreakZ
*$
```

MOSFET MODEL

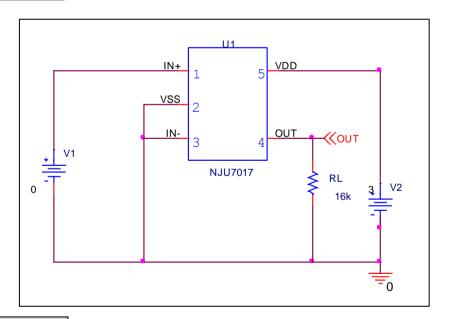
Pspice model	Model description		
parameter			
LEVEL			
L	Channel Length		
W	Channel Width		
KP	Transconductance		
RS	Source Ohmic Resistance		
RD	Ohmic Drain Resistance		
VTO	Zero-bias Threshold Voltage		
RDS	Drain-Source Shunt Resistance		
TOX	Gate Oxide Thickness		
CGSO	Zero-bias Gate-Source Capacitance		
CGDO	Zero-bias Gate-Drain Capacitance		
CBD	Zero-bias Bulk-Drain Junction Capacitance		
MJ	Bulk Junction Grading Coefficient		
PB	Bulk Junction Potential		
FC	Bulk Junction Forward-bias Capacitance Coefficient		
RG	Gate Ohmic Resistance		
IS	Bulk Junction Saturation Current		
N	Bulk Junction Emission Coefficient		
RB	Bulk Series Resistance		
PHI	Surface Inversion Potential		
GAMMA	Body-effect Parameter		
DELTA	Width effect on Threshold Voltage		
ETA	Static Feedback on Threshold Voltage		
THETA	Modility Modulation		
KAPPA	Saturation Field Factor		
VMAX	Maximum Drift Velocity of Carriers		
XJ	Metallurgical Junction Depth		
UO	Surface Mobility		

Output Voltage Swing

Simulation result



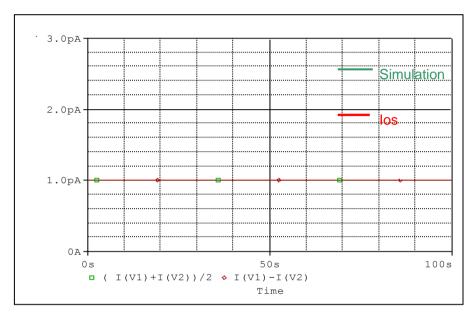
Evaluation Circuit



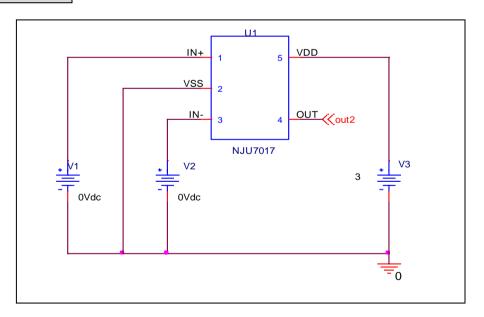
	Measurement	Simulation	%Error
V _{OM} (V)	2.900	2.907	0.238

Input Current

Simulation result



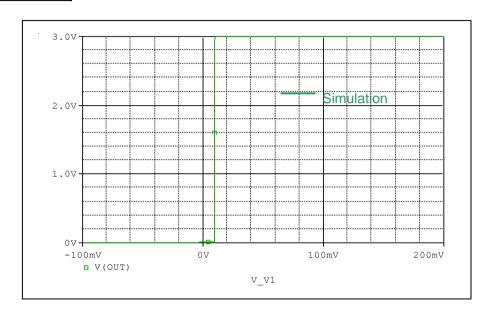
Evaluation Circuit



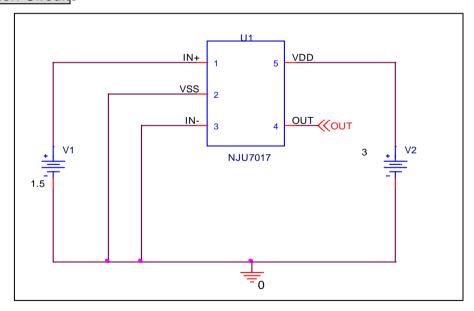
	Measurement	Simulation	% Error
I _b (pA)	1.000	1.000	0.000
I _{os} (pA)	1.000	1.000	0.000

Input Offset Voltage

Simulation result



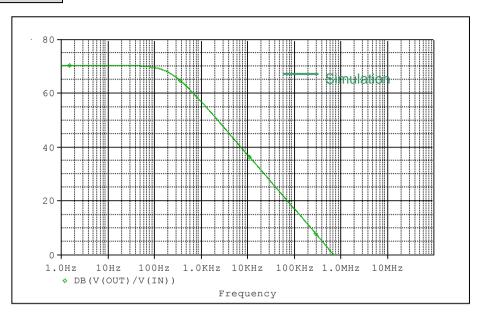
Evaluation Circuito



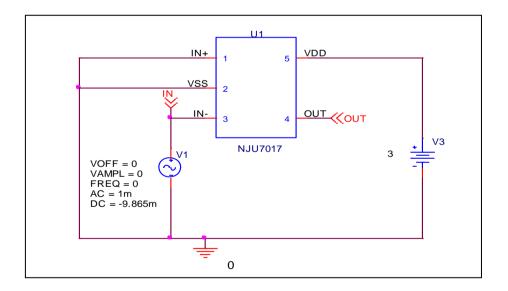
	Measurement	Simulation	%Error
V _{os} (mV)	10.000	9.865	-1.350

Open loop Voltage Gain

Simulation result



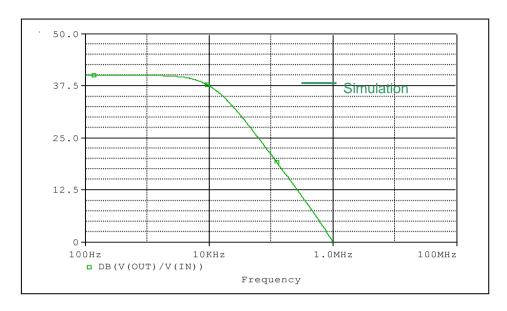
Evaluation Circuit



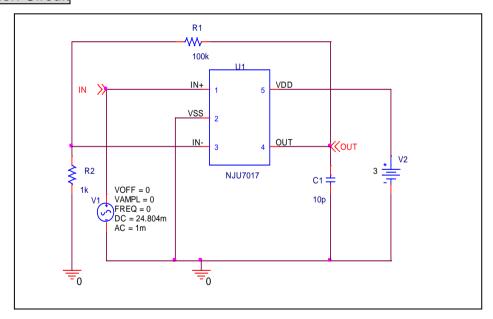
	Measurement	Simulation	%Error
Av (dB)	70.000	70.479	0.684

Unity Gain Frequency

Simulation result



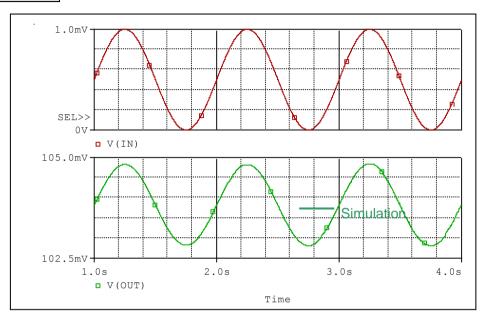
Evaluation Circuit



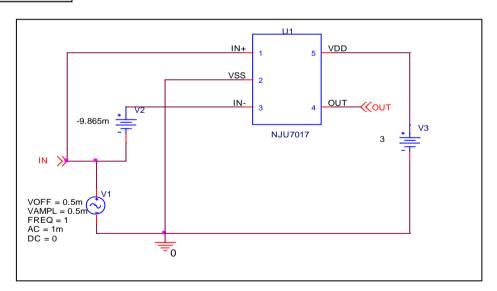
A _V =40dB,C _L =10pF	Measurement	Simulation	%Error
Ft(MHz)	1.000	1.003	0.300

Common-Mode Rejection Ratio

Simulation result



Evaluation Circuit

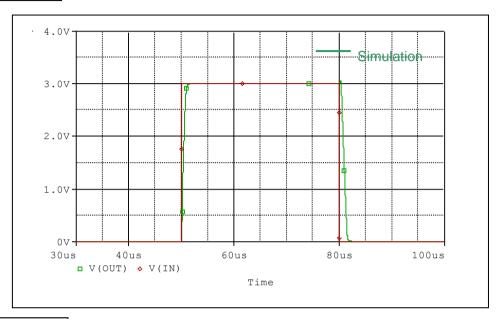


CMRR = AV/ACM = 20* LOG(3341.5657/(2.0096m/1m))

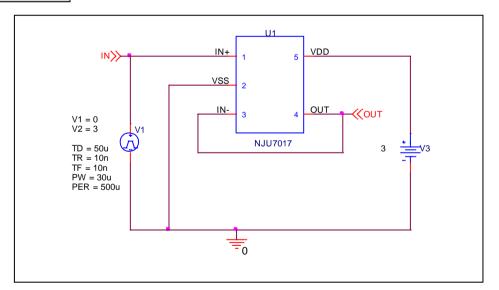
_	Measurement	Simulation	%Error
CMRR (dB)	65.000	64.416	-0.898

Slew Rate

Simulation result



Evaluation Circuit



	Measurement	Simulation	% Error
SR (V/us)	3.700	3.679	-0.568